## Notice of References Cited Application/Control No. 10/664,514 Examiner Alex P. Rada Applicatit(s)/Patent Under Reexamination SCHNEIDER ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0071557	06-2002	Nguyen, Binh T.	380/251
	В	US-6,071,190	06-2000	Weiss et al.	463/25
	С	US-6,456,716	09-2002	Arnold, Terry Sutton	380/277
	D	US-4,200,770	04-1980	Hellman et al.	380/30
	Ε	US-2002/0165023	11-2002	Brosnan et al.	463/29
	F	US-2002/0049909	04-2002	Jackson et al.	713/188
	G	US-6,364,769	04-2002	Weiss et al.	463/29
	Н	US-6,117,011	09-2000	Lvov, Denis Ernestovich	463/25
	1	US-2002/0152120	10-2002	Howington, David K.	705/14
	7	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.